

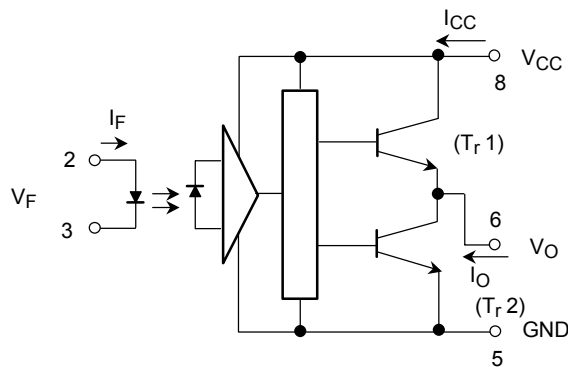
# TLP251

- Inverter For Air Conditionor
- Induction Heating
- Transistor Inverter
- Power MOS FET Gate Drive
- IGBT Gate Drive

The TOSHIBA TLP251 consists of a GaAlAs light emitting diode and a integrated photodetector.  
 This unit is 8-lead DIP package.  
 TLP251 is suitable for gate driving circuit of IGBT or power MOS FET.  
 Especially TLP251 is capable of "direct" gate drive of lower power IGBTs.  
 (~15A)

- Input threshold current:  $I_F=5\text{mA}(\text{max.})$
- Supply current ( $I_{CC}$ ):  $11\text{mA}(\text{max.})$
- Supply voltage ( $V_{CC}$ ):  $10\text{--}35\text{V}$
- Output current ( $I_O$ ):  $\pm 0.4\text{A}(\text{max.})$
- Switching time ( $t_{pLH} / t_{pHL}$ ):  $1\mu\text{s}(\text{max.})$
- Isolation voltage:  $2500\text{Vrms}(\text{min.})$
- UL recognized: UL1577, file no.E67349

### Schematic

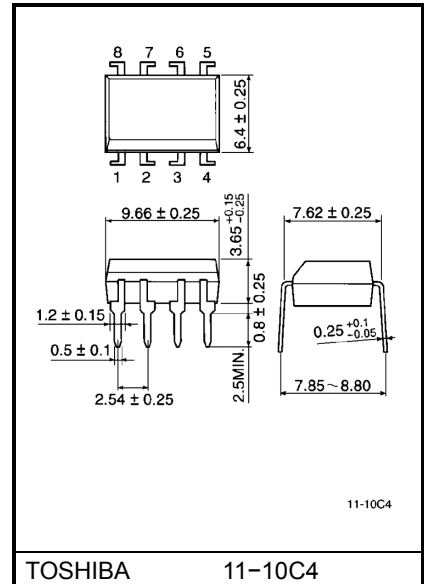


A  $0.1\mu\text{F}$  bypass capacitor must be connected between pin 8 and 5(see Note 5).

### Truth Table

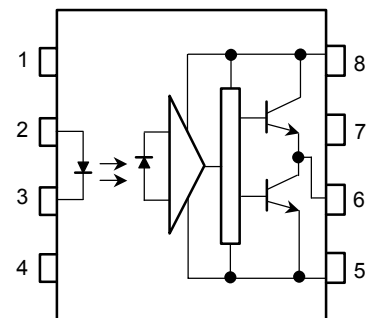
		Tr1	Tr2
Input	On	On	Off
LED	Off	Off	On

Unit in mm



TOSHIBA 11-10C4  
 Weight: 0.54g

### Pin Configuration (top view)



- 1 : N.C.
- 2 : Anode
- 3 : Cathode
- 4 : N.C.
- 5 : Gnd
- 6 :  $V_O$  (Output)
- 7 : N.C.
- 8 :  $V_{CC}$

## Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
LED	Forward current	$I_F$	20	mA	
	Forward current derating (Ta ≥ 70°C)	$\Delta I_F / \Delta T_a$	- 0.36	mA / °C	
	Peak transient forward current (Note 1)	$I_{FPT}$	1	A	
	Reverse voltage	$V_R$	5	V	
	Junction temperature	$T_j$	125	°C	
Detector	“H” peak output current ( $P_W \leq 2.0\mu s$ , $f \leq 15kHz$ ) (Note 2)		$I_{OPH}$	- 0.4	A
	“L” peak output current ( $P_W \leq 2.0\mu s$ , $f \leq 15kHz$ ) (Note 2)		$I_{OPL}$	0.4	A
	Output voltage	(Ta ≤ 70°C)	$V_O$	35	V
		(Ta = 85°C)		24	
	Supply voltage	(Ta ≤ 70°C)	$V_{CC}$	35	V
		(Ta = 85°C)		24	
	Output voltage derating (Ta ≥ 70°C)		$\Delta V_O / \Delta T_a$	- 0.73	V / °C
	Supply voltage derating (Ta ≥ 70°C)		$\Delta V_{CC} / \Delta T_a$	- 0.73	V / °C
	Junction temperature		$T_j$	125	°C
	Operating frequency (Note 3)		$f$	25	kHz
Operating temperature range		$T_{opr}$	-20~85	°C	
Storage temperature range		$T_{stg}$	-55~125	°C	
Lead soldering temperature(10s)		$T_{sol}$	260	°C	
Isolation voltage (AC, 1min., R.H.≤ 60%) (Note 4)		$BV_S$	2500	Vrms	

(Note 1) Pulse width  $P_W \leq 1\mu s$ , 300pps

(Note 2) Exponential waveform

(Note 3) Exponential waveform,  $I_{OPH} \leq -0.25A(\leq 2.0\mu s)$ ,  $I_{OPL} \leq +0.25A(\leq 2.0\mu s)$

(Note 4) Device considered a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.

(Note 5) A ceramic capacitor(0.1 $\mu F$ )should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching property. The total lead length between capacitor and coupler should not exceed 1cm.

## Recommended Operating Conditions

Characteristic	Symbol	Min.	Typ.	Max.	Unit
Input current, on	$I_{F(ON)}$	7	8	10	mA
Input voltage, off	$V_{F(OFF)}$	0	—	0.8	V
Supply voltage	$V_{CC}$	10	—	30   20	V
Peak output current	$I_{OPH} / I_{OPL}$	—	—	±0.1	A
Operating temperature	$T_{opr}$	-20	25	70   85	°C

## Electrical Characteristics (Ta = -20~70°C, unless otherwise specified)

Characteristic		Symbol	Test Circuit	Test Condition	Min.	Typ.*	Max.	Unit	
Input forward voltage		$V_F$	—	$I_F = 10 \text{ mA}$ , $T_a = 25^\circ\text{C}$	—	1.6	1.8	V	
Temperature coefficient of forward voltage		$\Delta V_F / \Delta T_a$	—	$I_F = 10 \text{ mA}$	—	-2.0	—	mV / °C	
Input reverse current		$I_R$	—	$V_R = 5\text{V}$ , $T_a = 25^\circ\text{C}$	—	—	10	μA	
Input capacitance		$C_T$	—	$V = 0$ , $f = 1\text{MHz}$ , $T_a = 25^\circ\text{C}$	—	45	250	pF	
Output current	“H” level	$I_{OPH}$	3	$V_{CC}=30\text{V}$ (*1)	$I_F = 10\text{mA}$ $V_{8-6} = 4\text{V}$	-0.1	-0.25	—	A
	“L” level	$I_{OPL}$	2		$I_F = 0$ $V_{6-5} = 2.5\text{V}$	0.1	0.2	—	
Output voltage	“H” level	$V_{OH}$	4	$V_{CC1} = +15\text{V}$ , $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$ , $I_F = 5\text{mA}$	11	13.2	—	V	
	“L” level	$V_{OL}$	5		$V_{CC1} = +15\text{V}$ , $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$ , $V_F = 0.8\text{V}$	—	-14.5		-12.5
Supply current	“H” level	$I_{CCH}$	—	$V_{CC} = 30\text{V}$ , $I_F = 10\text{mA}$ $T_a = 25^\circ\text{C}$	—	7.5	—	mA	
					—	—	11		
	“L” level	$I_{CCL}$	—		$V_{CC} = 30\text{V}$ , $I_F = 0\text{mA}$ $T_a = 25^\circ\text{C}$	—	8		—
						—	—		11
Threshold input current	“Output L → H”	$I_{FLH}$	—	$V_{CC1} = +15\text{V}$ , $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$ , $V_O > 0\text{V}$	—	1.2	5	mA	
Threshold input voltage	“Output H → L”	$V_{FLH}$	—	$V_{CC1} = +15\text{V}$ , $V_{EE1} = -15\text{V}$ $R_L = 200\Omega$ , $V_O < 0\text{V}$	0.8	—	—	V	
Supply voltage		$V_{CC}$	—		10	—	35	V	
Capacitance (input-output)		$C_s$	—	$V_s = 0$ , $f = 1\text{MHz}$ $T_a = 25^\circ\text{C}$	—	1.0	2.0	pF	
Resistance (input-output)		$R_s$	—	$V_s = 500\text{V}$ , $T_a = 25^\circ\text{C}$ $R.H. \leq 60\%$	$1 \times 10^{12}$	$10^{14}$	—	Ω	

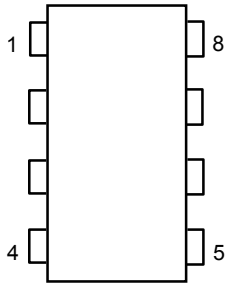
\* All typical values are at  $T_a=25^\circ\text{C}$  (\*1): Duration of  $I_O$  time  $\leq 50\mu\text{s}$

## Switching Characteristics (Ta = -20~70°C, unless otherwise specified)

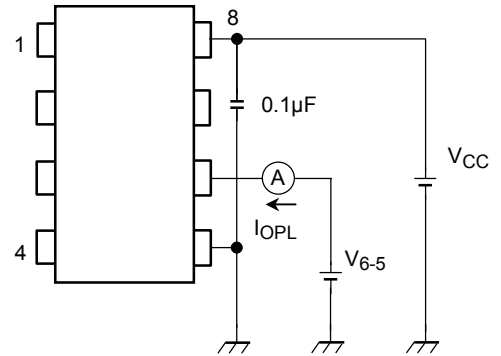
Characteristic		Symbol	Test Cir-cuit	Test Condition	Min.	Typ.*	Max.	Unit
Propagation delay time	L→H	t <sub>pLH</sub>	6	I <sub>F</sub> = 8mA V <sub>CC1</sub> = +15V, V <sub>EE1</sub> = -15V R <sub>L</sub> = 200 Ω	—	0.25	1.0	μs
	H→L	t <sub>pHL</sub>			—	0.25	1.0	
Output rise time		t <sub>r</sub>			—	—	—	
Output fall time		t <sub>f</sub>			—	—	—	
Common mode transient immunity at high level output		C <sub>MH</sub>	7	V <sub>CM</sub> = 600V, I <sub>F</sub> = 8mA, V <sub>CC</sub> = 30V, Ta = 25°C	-5000	—	—	V / μs
Common mode transient immunity at low level output		C <sub>ML</sub>	7	V <sub>CM</sub> = 600V, I <sub>F</sub> = 0mA, V <sub>CC</sub> = 30V, Ta = 25°C	5000	—	—	V / μs

\*All typical values are at Ta=25°C

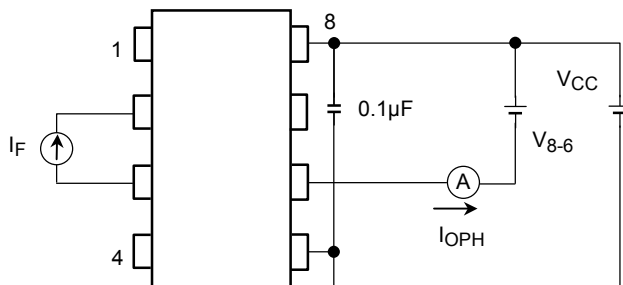
**Test Circuit 1:**



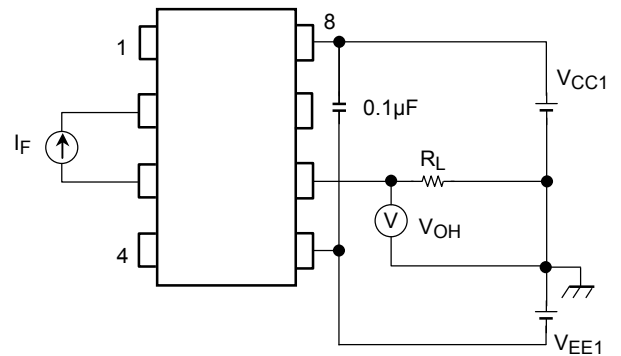
**Test Circuit 2:  $I_{OPL}$**



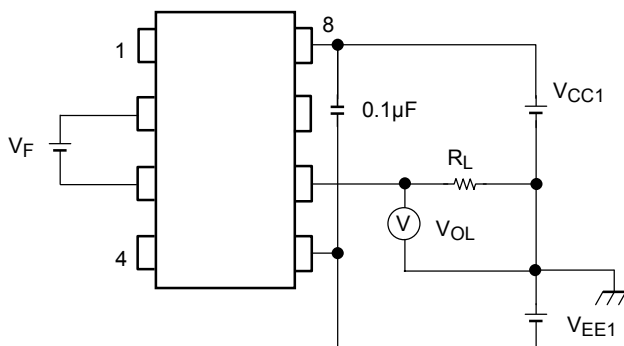
**Test Circuit 3:  $I_{OPH}$**



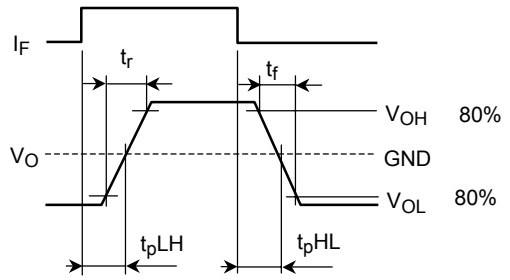
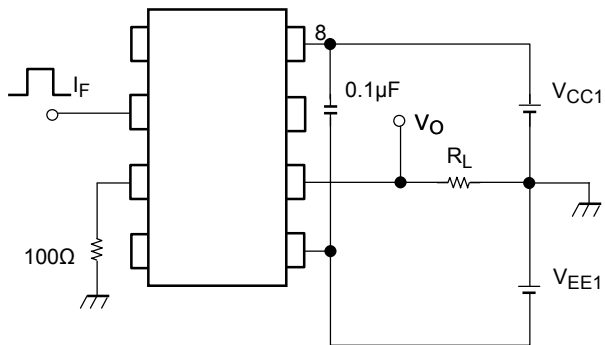
**Test Circuit 4:  $V_{OH}$**



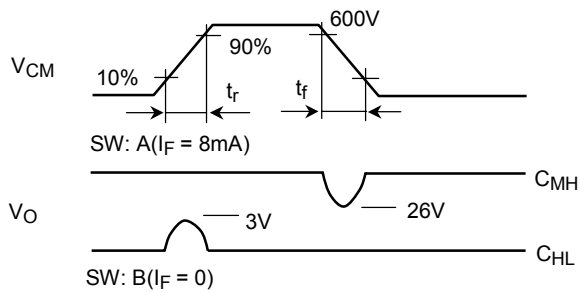
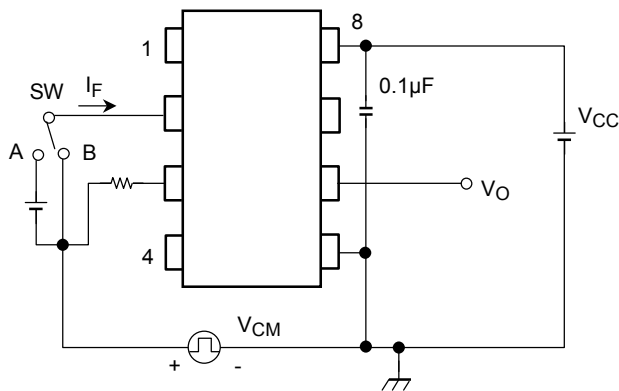
**Test Circuit 5:  $V_{OL}$**



**Test Circuit 6:  $t_{pLH}$ ,  $t_{pHL}$ ,  $t_r$ ,  $t_f$**



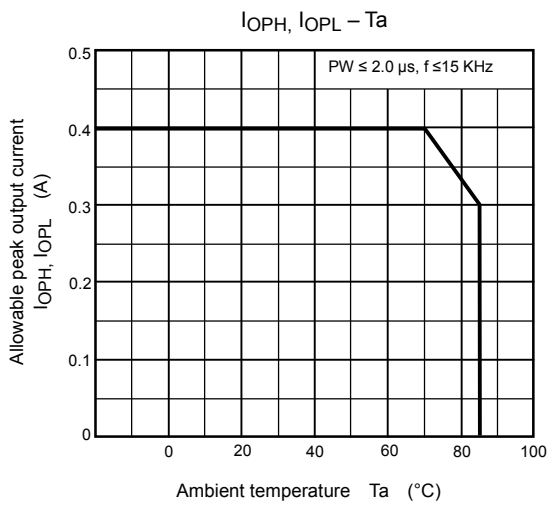
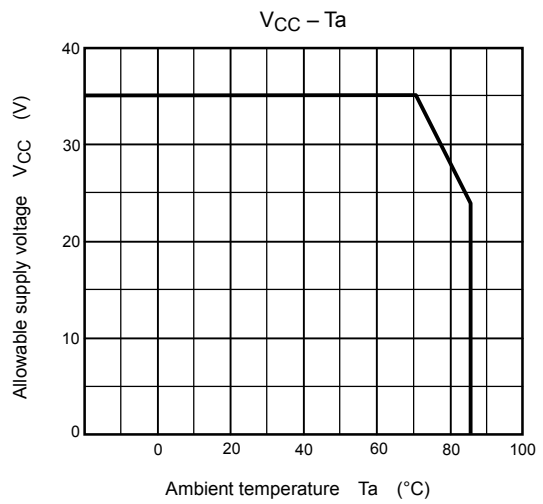
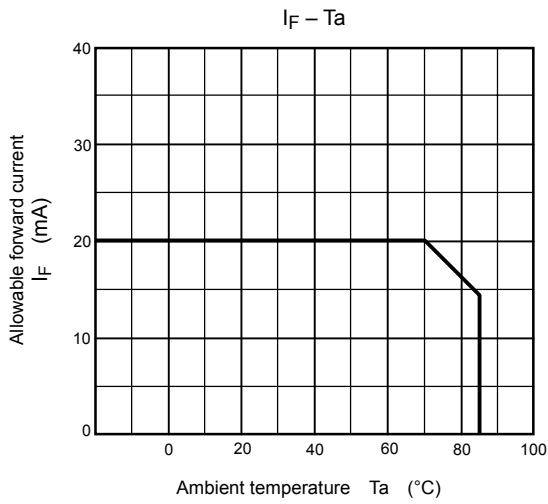
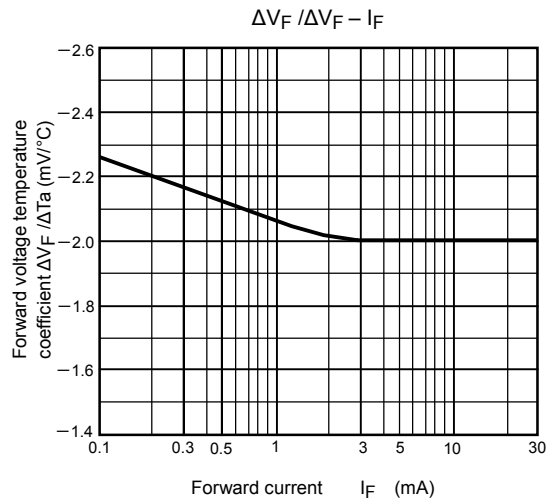
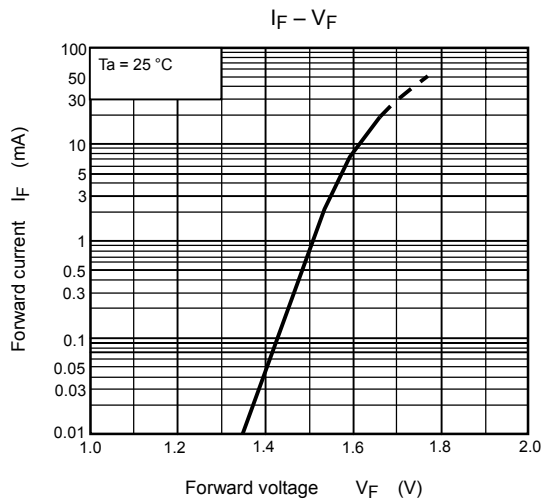
**Test Circuit 7:  $C_{MH}$ ,  $C_{ML}$**



$$C_{ML} = \frac{480(V)}{t_r(\mu s)}$$

$$C_{MH} = \frac{480(V)}{t_f(\mu s)}$$

$C_{ML}$  ( $C_{MH}$ ) is the maximum rate of rise (fall) of the common mode voltage that can be sustained with the output voltage in the low (high) state.



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